

MLC-B Test Report

Summary Report Page – All Tests

SNIA Solid State Storage Performance Test Specification (PTS)						Rev. PTS 1.0	
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Device Under Test (DUT)	MLC-B	SNIA SSS PTS Summary Report		Calypso Systems, Inc.		CALYPSO Systems	
DEVICE INFORMATION		TEST HARDWARE PLATFORM		TEST SOFTWARE		REPORT DATE	
SERIAL NO.	0000-1111-FFFF	SYSTEM	Calypso RTP 2.0	SYS OS	CENT OS 5.6	Report	06DEC11
FIRMWARE REV.	02HD	Motherboard/cpu	Intel 5520HC / W5580	SW TOOL	Calypso CTS 6.5	Test Run	01NOV – 04DEC11
USER CAPACITY	MLC 160 GB	RAM	12GB ECC DDR3	SW Rev	1.19.10	Test Sponsor	Calypso
DEVICE INTERFACE	3Gb/s SATA	Device Interface	LSA 9212-e 6Gb/s HBA	Release	Nov. 2011	Auditor	N/A

Testing Summary: Tests Run

PTS-C	TEST	Purge	DP	OIO	WIPC		WDPC		STEADY STATE	
					PC AR	TEST AR	AR AMT	SEGMENTS	WORKLOAD	TIME/GB
7.0	WSAT - OPTIONAL	Security Erase	RND	TC 16 QD 2	100%	100%	N/A	N/A	RND 4KiB W	12 Hrs 250 GB

PTS-C	TEST	Purge	DP	OIO	WIPC		WDPC		STEADY STATE	
					PC AR	TEST AR	AR AMT	SEGMENTS	WORKLOAD	ROUNDS
8.0	IOPS - REQUIRED	Security Erase	RND	TC 32 QD 1	100%	100%	16 GiB	2048	IOPS LOOP	9 - 13

PTS-C	TEST	Purge	DP	OIO	WIPC		WDPC		STEADY STATE	
					PC AR	TEST AR	AR AMT	SEGMENTS	WORKLOAD	ROUNDS
9.0	THROUGHPUT - REQUIRED	Security Erase	RND	TC 1 QD 2	100%	100%	16 GiB	2048	SEQ 1024KiB	1 - 5

PTS-C	TEST	Purge	DP	OIO	WIPC		WDPC		STEADY STATE	
					PC AR	TEST AR	AR AMT	SEGMENTS	WORKLOAD	ROUNDS
10.0	LATENCY - REQUIRED	Security Erase	RND	TC 1 QD 1	100%	100%	16 GiB	2048	LAT LOOP	12 - 16

Test Sponsor – Special Notes

ITEM	NOTATION	COMMENTS

MLC-B Test Report

Summary Report Page - WSAT

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Device Under Test (DUT)	MLC-B	SNIA SSS PTS Summary Report		Calypso Systems, Inc.		CALYPSO Systems	
DEVICE INFORMATION		TEST HARDWARE PLATFORM		TEST SOFTWARE		REPORT DATE	
SERIAL NO.	0000-1111-FFFF	SYSTEM	Calypso RTP 2.0	SYS OS	CENT OS 5.6	Report	06DEC11
FIRMWARE REV.	02HD	Motherboard/cpu	Intel 5520HC / W5580	SW TOOL	Calypso CTS 6.5	Test Run	01NOV - 04DEC11
USER CAPACITY	MLC 160 GB	RAM	12GB ECC DDR3	SW Rev	1.19.10	Test Sponsor	Calypso
DEVICE INTERFACE	3 Gb/s SATA	Device Interface	LSA 9212-e 6Gb/s HBA	Release	Nov. 2011	Auditor	N/A

Test Description

Purpose	To observe the drive's performance evolution from a PURGED state to that of SETTLED state
Test Outline	Uses total outstanding IO settings that maximizes RND 4KiB Writes, first PURGE the drive, followed by immediate continuous RND 4KiB (4K-aligned) writes for lesser of 4 x User Capacity or 24 Hours
Preconditioning	FOB - No Pre Conditioning - PURGE followed by Test (note: tests may be run longer for plotting clarity)

Test Set Up

PTS-C	TEST	Purge	DP	OIO	WIPC		WDPC		STEADY STATE	
					PC AR	TEST AR	AR AMT	SEGMENTS	WORKLOAD	TIME/GB
7.0	WSAT - OPTIONAL	Security Erase	RND	TC 16 QD 2	100%	100%	N/A	N/A	RND 4KiB W	12 Hrs 250 GB

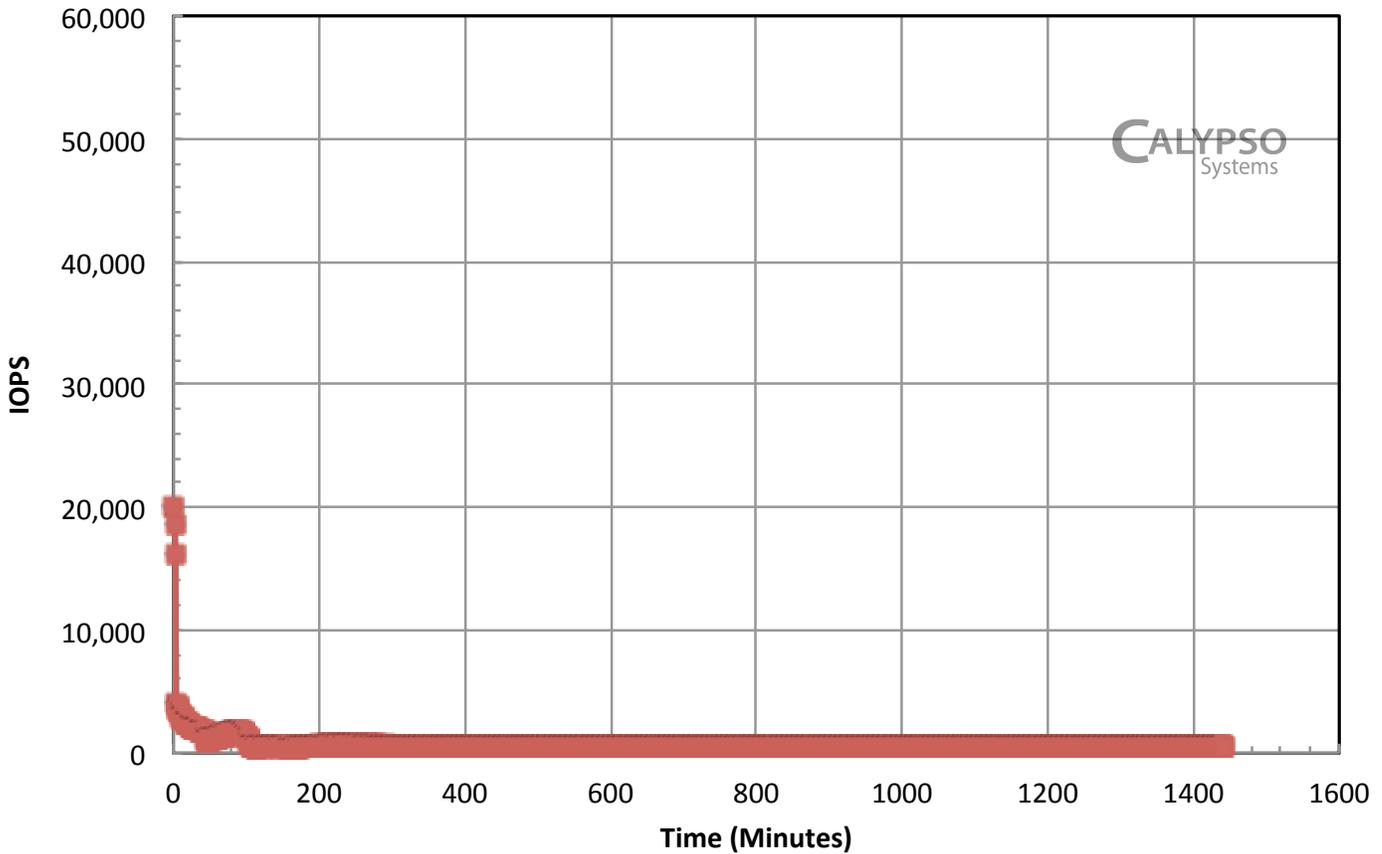
Select Performance Data

FOB IOPS	Steady State IOPS	Time	Total GB Written
20,364	658	12 Hours	250 GB

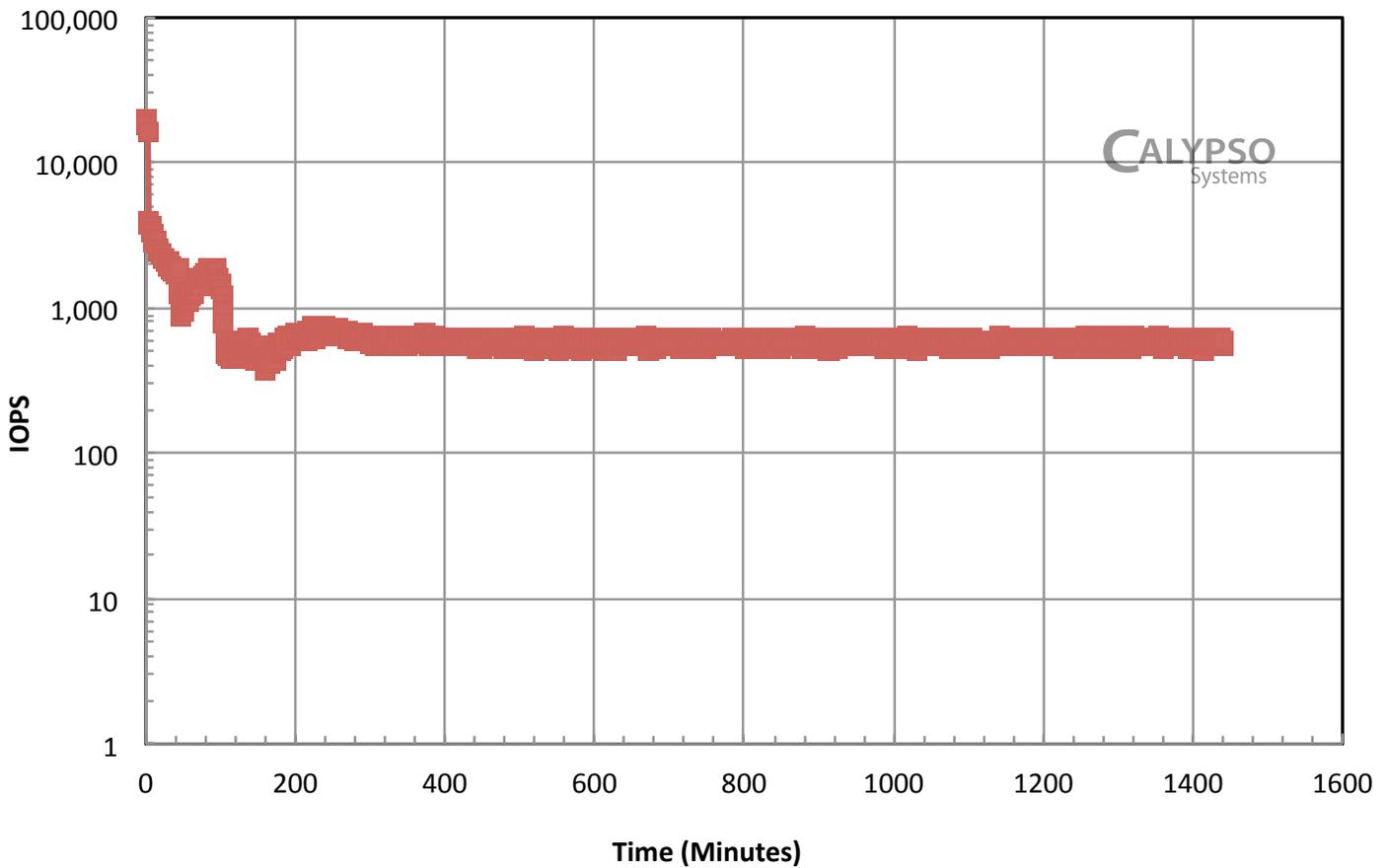
Test Sponsor – Special Notes

ITEM	NOTATION	COMMENTS

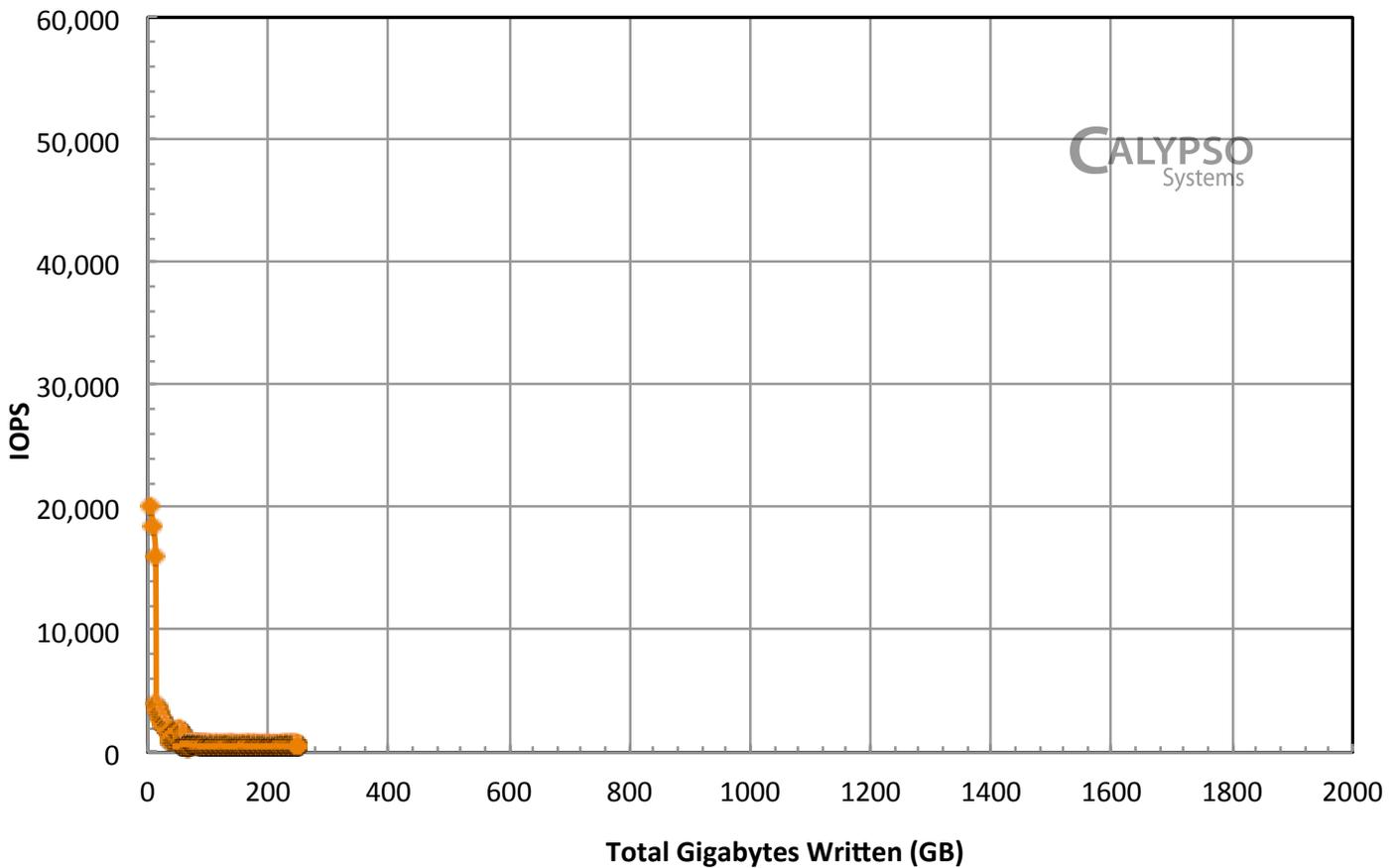
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Client WSAT (OPTIONAL) - Report Page			
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)			Rev. PTS-C 1.0
			Page 1 of 4
Device Under Test (DUT)	VENDOR: ABC CO.	SSD MODEL NO: MLC-B 160 GB	TEST SPONSOR CALYPSO Systems
Serial No.	0000-1111-FFFF	DUT Preparation	Test Loop Parameters
Firmware Rev	02HD	Purge	Security Erase
Capacity	160 GB	Pre-Conditioning	
NAND Type	MLC	Workload Independent	N/A
Device I/F	3 Gb/s SATA	Workload Dep.	RND 4KiB
Test Platform	RTP 2.0 CTS 6.5		
		REQUIRED:	Steady State
		Data Pattern	Convergence
		Tester's Choice:	N/A
		OIO/Thread (QD)	Rounds
		Thread Count (TC)	N/A
			PC AR
			100%
			AR AMOUNT
			100%
			AR Segments
			N/A
Client IOPS (Linear) vs Time (Linear)			



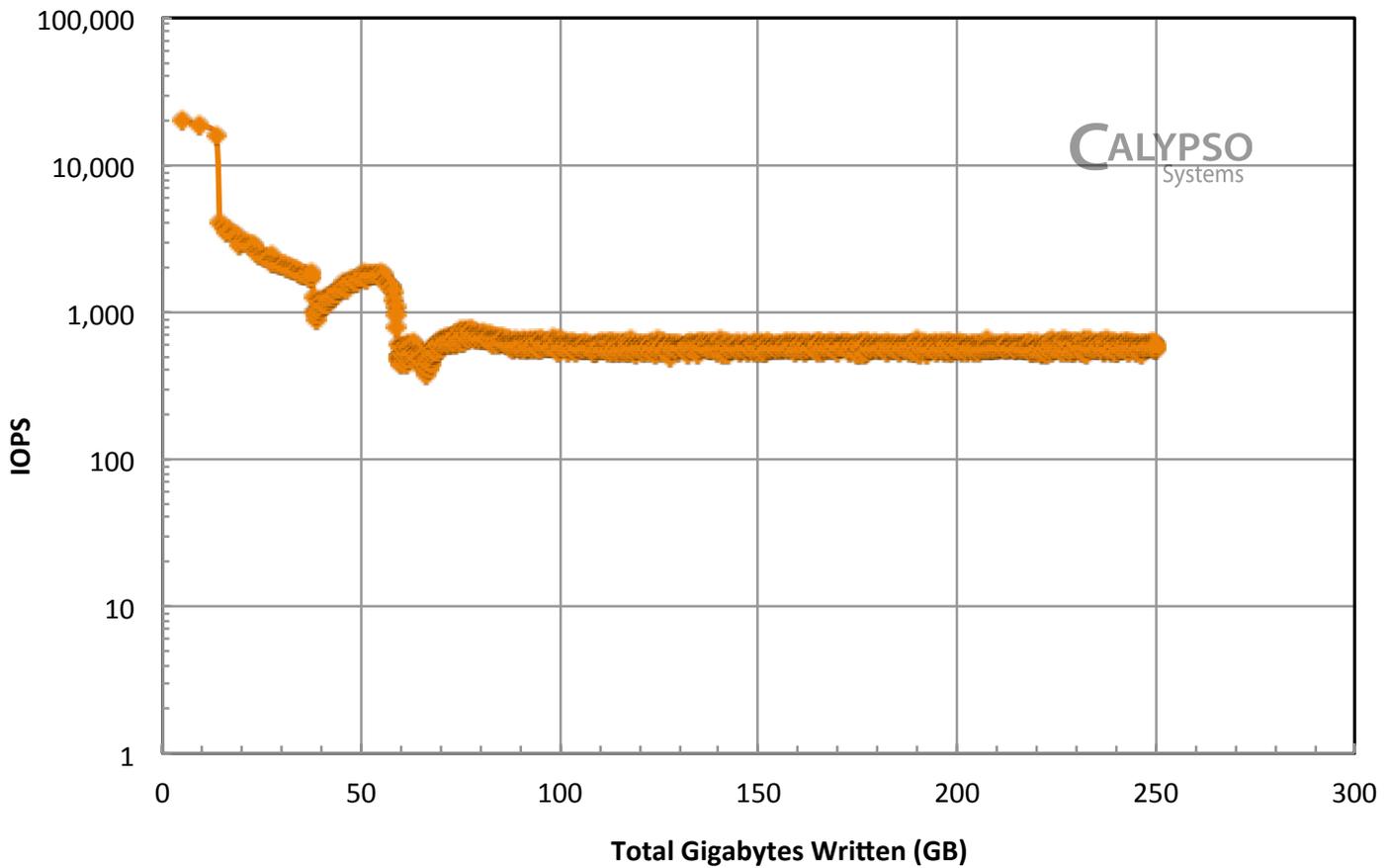
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Client WSAT (OPTIONAL) - Report Page			
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)			Rev. PTS-C 1.0
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Device Under Test (DUT)	VENDOR: ABC CO.	SSD MODEL NO: MLC-B 160 GB	TEST SPONSOR CALYPSO Systems
Serial No.	0000-1111-FFFF	DUT Preparation	Test Loop Parameters
Firmware Rev	02HD	Purge	Security Erase
Capacity	160 GB	Pre-Conditioning	
NAND Type	MLC	Workload Independent	N/A
Device I/F	3 Gb/s SATA	Workload Dep.	RND 4KiB
Test Platform	RTP 2.0 CTS 6.5		
		REQUIRED:	
		Data Pattern	RND
		Tester's Choice:	
		OIO/Thread (QD)	2
		Thread Count (TC)	16
		Steady State	
		Convergence	N/A
		Rounds	N/A
		PC AR	100%
		AR AMOUNT	100%
		AR Segments	N/A
Client IOPS (Log10) vs Time (Linear)			



Test Run Date: 11/21/2011 06:35 AM		Report Run Date: 11/24/2011 04:44 PM	
Client WSAT (OPTIONAL) - Report Page			
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Device Under Test (DUT)	VENDOR: ABC CO.	SSD MODEL NO: MLC-B 160 GB	TEST SPONSOR CALYPSO Systems
Serial No.	0000-1111-FFFF	DUT Preparation	Test Loop Parameters
Firmware Rev	02HD	Purge	Security Erase
Capacity	160 GB	REQUIRED:	
NAND Type	MLC	Data Pattern	
Device I/F	3 Gb/s SATA	RND	
Test Platform	RTP 2.0 CTS 6.5	Tester's Choice:	
		OIO/Thread (QD)	2
		Thread Count (TC)	16
		Workload Independent	N/A
		Workload Dep.	RND 4KiB
		Convergence	N/A
		Rounds	N/A
		PC AR	100%
		AR AMOUNT	100%
		AR Segments	N/A
Client IOPS (Linear) vs Total Gigabytes Written (Linear)			



Test Run Date: 11/21/2011 06:35 AM		Report Run Date: 11/24/2011 04:44 PM	
Client WSAT (OPTIONAL) - Report Page			
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)			Rev. PTS-C 1.0
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Device Under Test (DUT)	VENDOR: ABC CO.	SSD MODEL NO: MLC-B 160 GB	TEST SPONSOR CALYPSO Systems
Serial No.	0000-1111-FFFF	DUT Preparation	Test Loop Parameters
Firmware Rev	02HD	Purge	Security Erase
Capacity	160 GB	Pre-Conditioning	
NAND Type	MLC	Workload Independent	N/A
Device I/F	3 Gb/s SATA	Workload Dep.	RND 4KiB
Test Platform	RTP 2.0 CTS 6.5		
		REQUIRED:	Steady State
		Data Pattern	RND
		Tester's Choice:	
		OIO/Thread (QD)	2
		Thread Count (TC)	16
		Convergence	N/A
		Rounds	N/A
		PC AR	100%
		AR AMOUNT	100%
		AR Segments	N/A
Client IOPS (Log10) vs Total Gigabytes Written (Lin)			



MLC-B Test Report

Summary Report Page - IOPS

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Device Under Test (DUT)	MLC-B	SNIA SSS PTS Summary Report		Calypso Systems, Inc.		CALYPSO Systems	
DEVICE INFORMATION		TEST HARDWARE PLATFORM		TEST SOFTWARE		REPORT DATE	
SERIAL NO.	0000-1111-FFFF	SYSTEM	Calypso RTP 2.0	SYS OS	CENT OS 5.6	Report	06DEC11
FIRMWARE REV.	02HD	Motherboard/cpu	Intel 5520HC / W5580	SW TOOL	Calypso CTS 6.5	Test Run	01NOV - 04DEC11
USER CAPACITY	MLC 256 GB	RAM	12GB ECC DDR3	SW Rev	1.19.10	Test Sponsor	Calypso
DEVICE INTERFACE	3 Gb/s SATA	Device Interface	LSA 9212-e 6Gb/s HBA	Release	Nov. 2011	Auditor	N/A

Test Description

Purpose	To measure RND IOPS matrix using different BS and R/W Mixes
Test Outline	PURGE, then apply preconditioning until Steady State is achieved according to the SNIA PTS
Preconditioning	PURGE followed by SNIA PTS prescribed WIPC & WDPC

Test Set Up

PTS-C	TEST	Purge	DP	OIO	WIPC		WDPC		STEADY STATE	
8.0	IOPS - REQUIRED	Security Erase	RND	TC 32 QD 1	PC AR	TEST AR	AR AMT	SEGMENTS	WORKLOAD	ROUNDS
					100%	100%	16 GiB	2048	IOPS LOOP	9 - 13

Select Performance Data

RND 4KiB W	RND 4KiB R	RND 8KiB W	RND 8KiB R
152	38,087	151	22,978

Test Sponsor – Special Notes

ITEM	NOTATION	COMMENTS

Test Run Date: 11/17/2011 10:54 AM

Report Run Date: 11/21/2011 04:47 PM

CLIENT IOPS (REQUIRED) - Report Page

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Device Under Test (DUT)

VENDOR:
ABC CO.

SSD MODEL NO:
MLC-B 160 GB

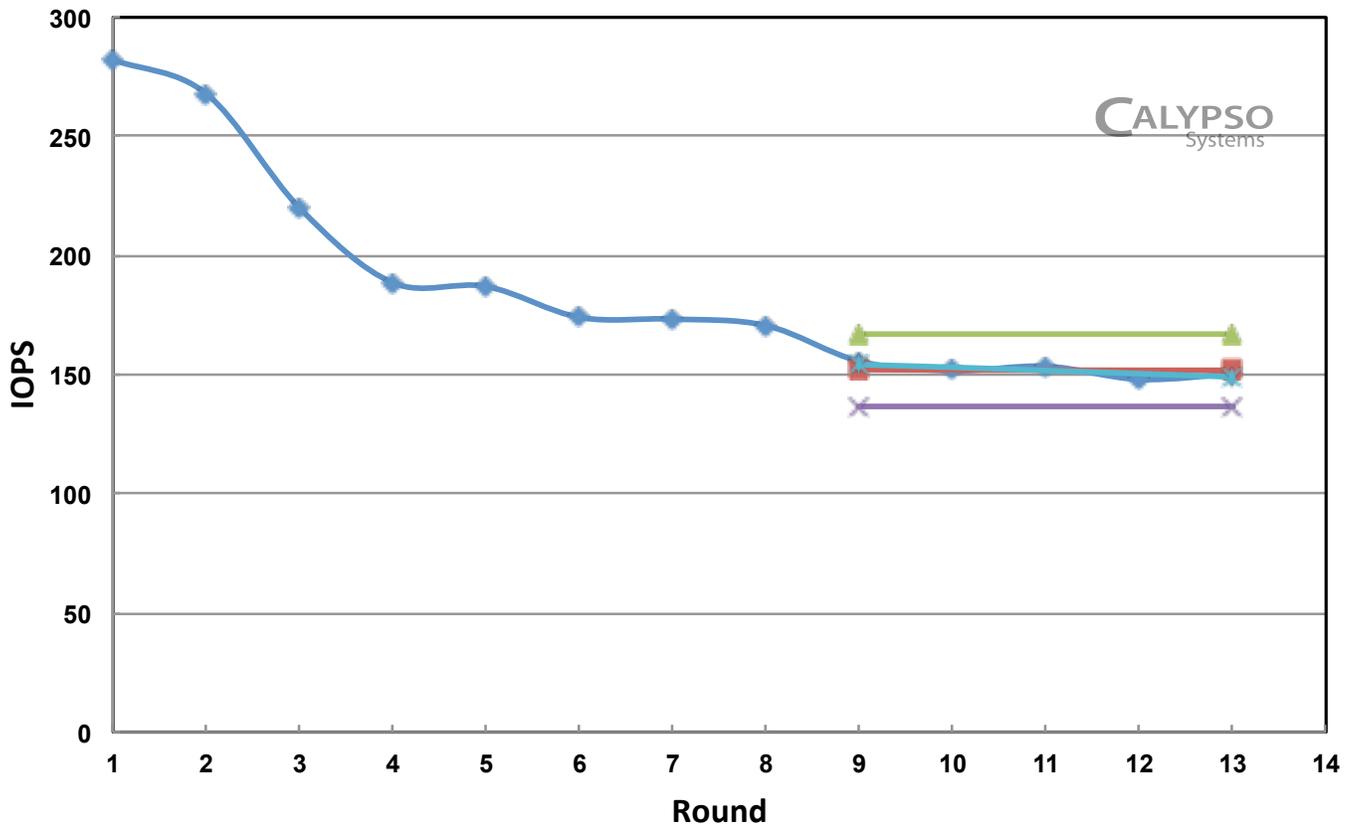
TEST SPONSOR



Serial No.	0000-1111-FFFF	DUT Preparation		Test Loop Parameters		Steady State	
Firmware Rev	02HD	Purge	Security Erase	REQUIRED: Data Pattern	RND	Convergence	YES
Capacity	160 GB	Pre-Conditioning				OIO/Thread (QD)	Rounds
NAND Type	MLC	Workload Independent	2X SEQ/128KiB	Tester's Choice: OIO/Thread (QD)	1	PC AR	100%
Device I/F	3 Gb/s SATA					AR AMOUNT	16 GiB
Test Platform	RTP 2.0 CTS 6.5	Workload Dep.	Full IOPS Loop	Thread Count (TC)	32	AR Segments	2048

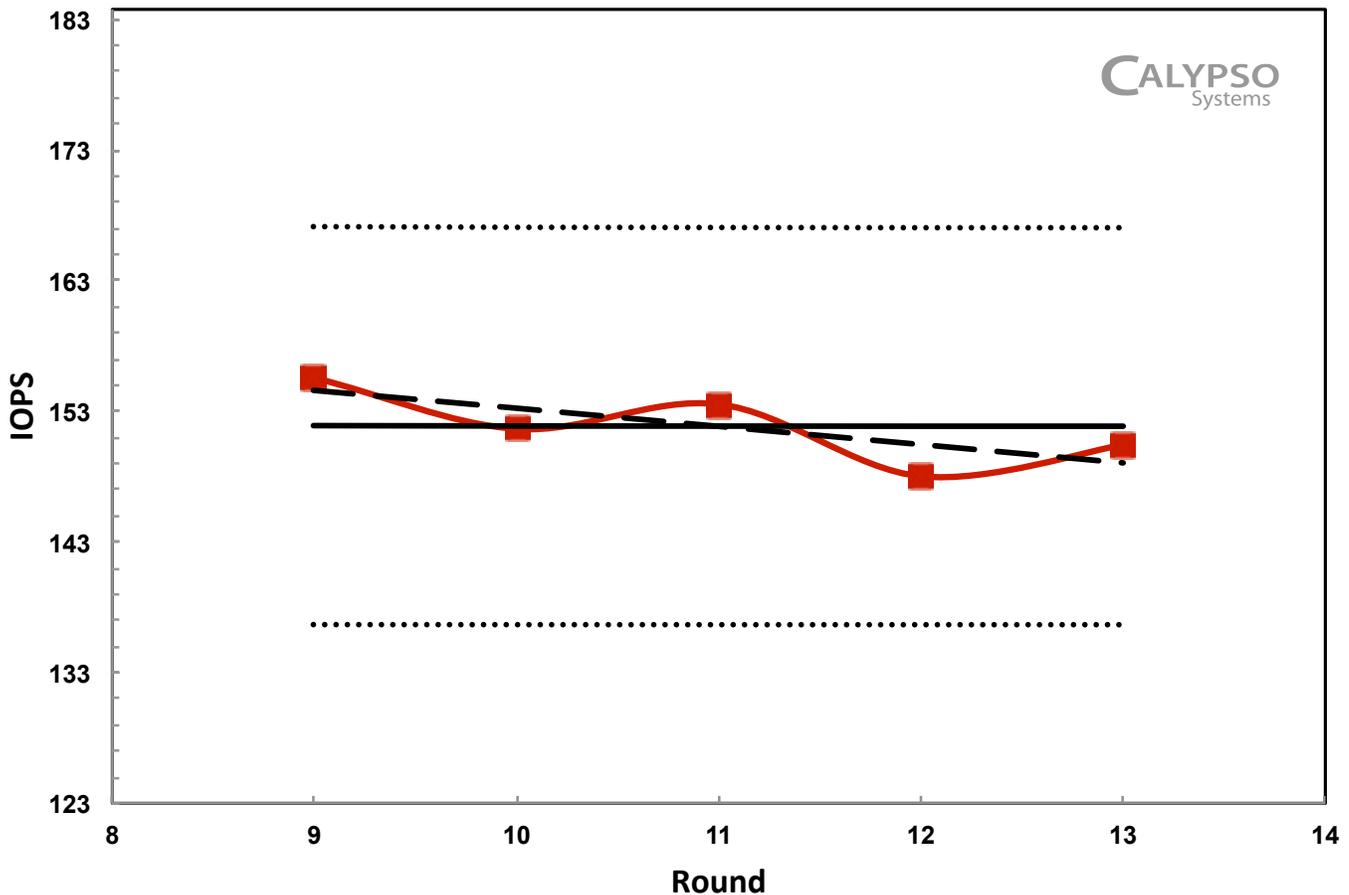
Steady State Measurement Window

Legend: IOPS (blue line with diamonds), Average (red line with squares), 110%*Average (green line with triangles), 90%*Average (purple line with crosses), Slope (cyan line with asterisks)



Test Run Date: 11/17/2011 10:54 AM		Report Run Date: 11/21/2011 04:47 PM	
CLIENT IOPS (REQUIRED) - Report Page			
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)			Rev. PTS-C 1.0
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Device Under Test (DUT)	VENDOR: ABC CO.	SSD MODEL NO: MLC-B 160 GB	TEST SPONSOR CALYPSO Systems
Serial No.	0000-1111-FFFF	DUT Preparation	Test Loop Parameters
Firmware Rev	02HD	Purge	Security Erase
Capacity	160 GB	REQUIRED:	
NAND Type	MLC	Data Pattern	
Device I/F	3 Gb/s SATA	RND	
Test Platform	RTP 2.0 CTS 6.5	Tester's Choice:	
		OIO/Thread (QD)	1
		Thread Count (TC)	32
		Workload	
		Independent	2X SEQ/128KiB
		Workload Dep.	Full IOPS Loop
		Steady State	
		Convergence	YES
		Rounds	9-13
		PC AR	100%
		AR AMOUNT	16 GiB
		AR Segments	2048
Steady State Measurement Window - RND/4KiB			

■ IOPS
 — Average
 110%*Average
 90%*Average
 - - - Slope



Steady State Determination Data

Average IOPS:	151.9
Allowed Maximum Data Excursion:	30.4
Measured Maximum Data Excursion:	7.6
Allowed Maximum Slope Excursion:	15.2
Measured Maximum Slope Excursion:	5.6
Least Squares Linear Fit Formula:	-1.403 * R + 167.292

Test Run Date:	11/17/2011 10:54 AM	Report Run Date:	11/21/2011 04:47 PM
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CLIENT IOPS (REQUIRED) - Report Page

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Device Under Test (DUT)	VENDOR: ABC CO.	SSD MODEL NO: MLC-B 160 GB	TEST SPONSOR	
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Serial No.	0000-1111-FFFF	DUT Preparation		Test Loop Parameters		Steady State	
Firmware Rev	02HD	Purge	Security Erase	REQUIRED: Data Pattern	RND	Convergence	YES
Capacity	160 GB	Pre-Conditioning				Tester's Choice: OIO/Thread (QD)	1
NAND Type	MLC	Workload Independent	2X SEQ/128KiB	Thread Count (TC)	32		
Device I/F	3 Gb/s SATA					Workload Dep.	Full IOPS Loop
Test Platform	RTP 2.0 CTS 6.5			AR Segments	2048		

CLIENT IOPS - ALL RW Mix & BS - Tabular Data

Block Size (KiB)	Read / Write Mix %						
	0/100	5/95	35/65	50/50	65/35	95/5	100/0
0.5	160.9	182.5	234.4	307.6	436.3	3,046.3	64,918.3
4	151.9	178.6	230.6	293.4	425.5	3,081.5	38,087.5
8	151.3	179.5	220.1	284.3	402.6	2,510.8	22,978.6
16	146.8	194.9	218.1	281.4	400.3	2,483.1	12,195.5
32	225.7	249.4	329.3	435.5	606.1	3,032.2	3,258.2
64	119.9	126.3	182.7	228.5	318.6	1,526.2	2,993.1
128	61.1	64.1	92.8	119.3	167.4	370.3	2,037.7
1024	8.4	8.7	13.1	17.7	24.6	164.9	252.3

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CLIENT IOPS (REQUIRED) - Report Page

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Device Under Test (DUT)

VENDOR:
ABC CO.

SSD MODEL NO:
MLC-B 160 GB

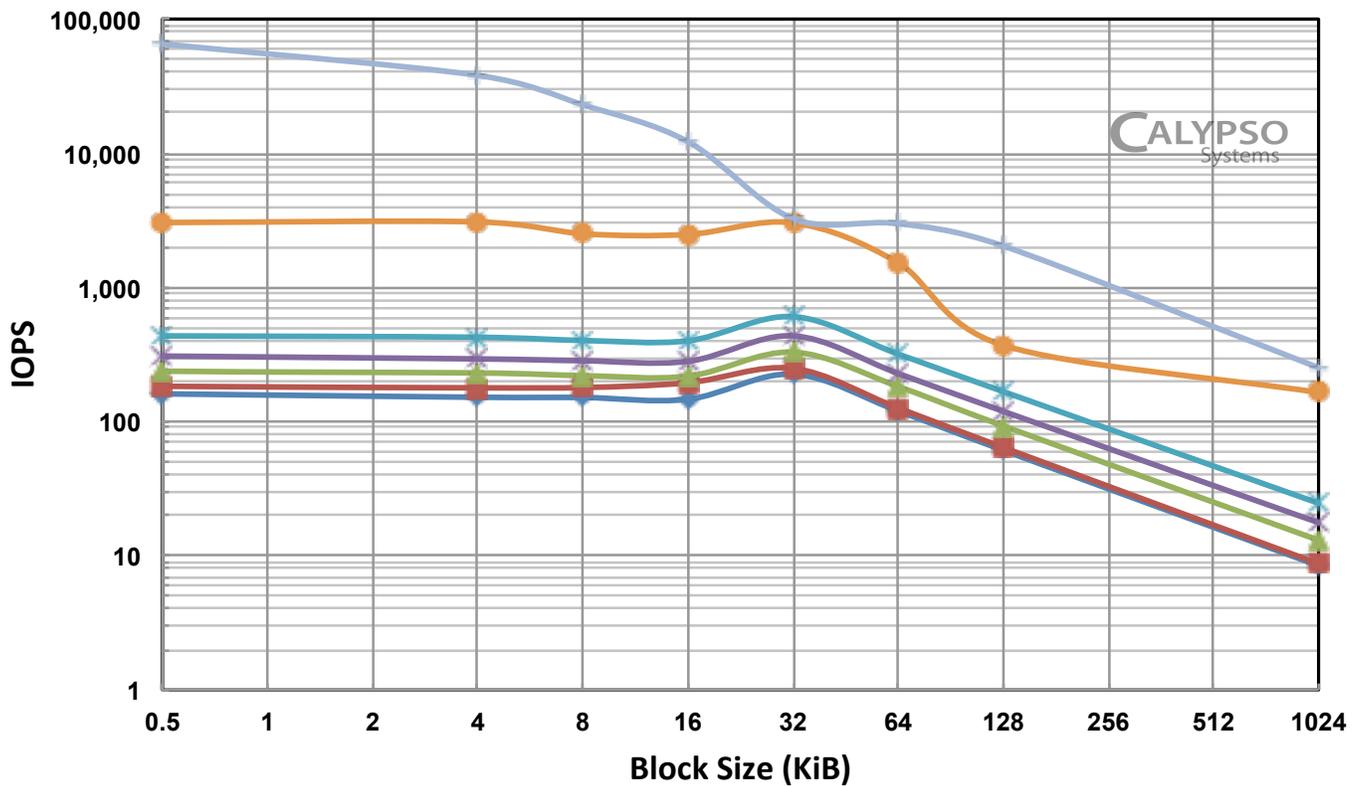
TEST SPONSOR



Serial No.	0000-1111-FFFF	DUT Preparation		Test Loop Parameters		Steady State	
Firmware Rev	02HD	Purge	Security Erase	REQUIRED: Data Pattern	RND	Convergence	YES
Capacity	160 GB	Pre-Conditioning				OIO/Thread (QD)	Rounds
NAND Type	MLC	Workload Independent	2X SEQ/128KiB	Tester's Choice: OIO/Thread (QD)	1	PC AR	100%
Device I/F	3 Gb/s SATA		Workload Dep.			Full IOPS Loop	Thread Count (TC)
Test Platform	RTP 2.0 CTS 6.5						AR Segments

IOPS - ALL RW Mix & BS - 2D Plot

0/100 5/95 35/65 50/50 65/35 95/5 100/0



Test Run Date: 11/17/2011 10:54 AM

Report Run Date: 11/21/2011 04:47 PM

CLIENT IOPS (REQUIRED) - Report Page

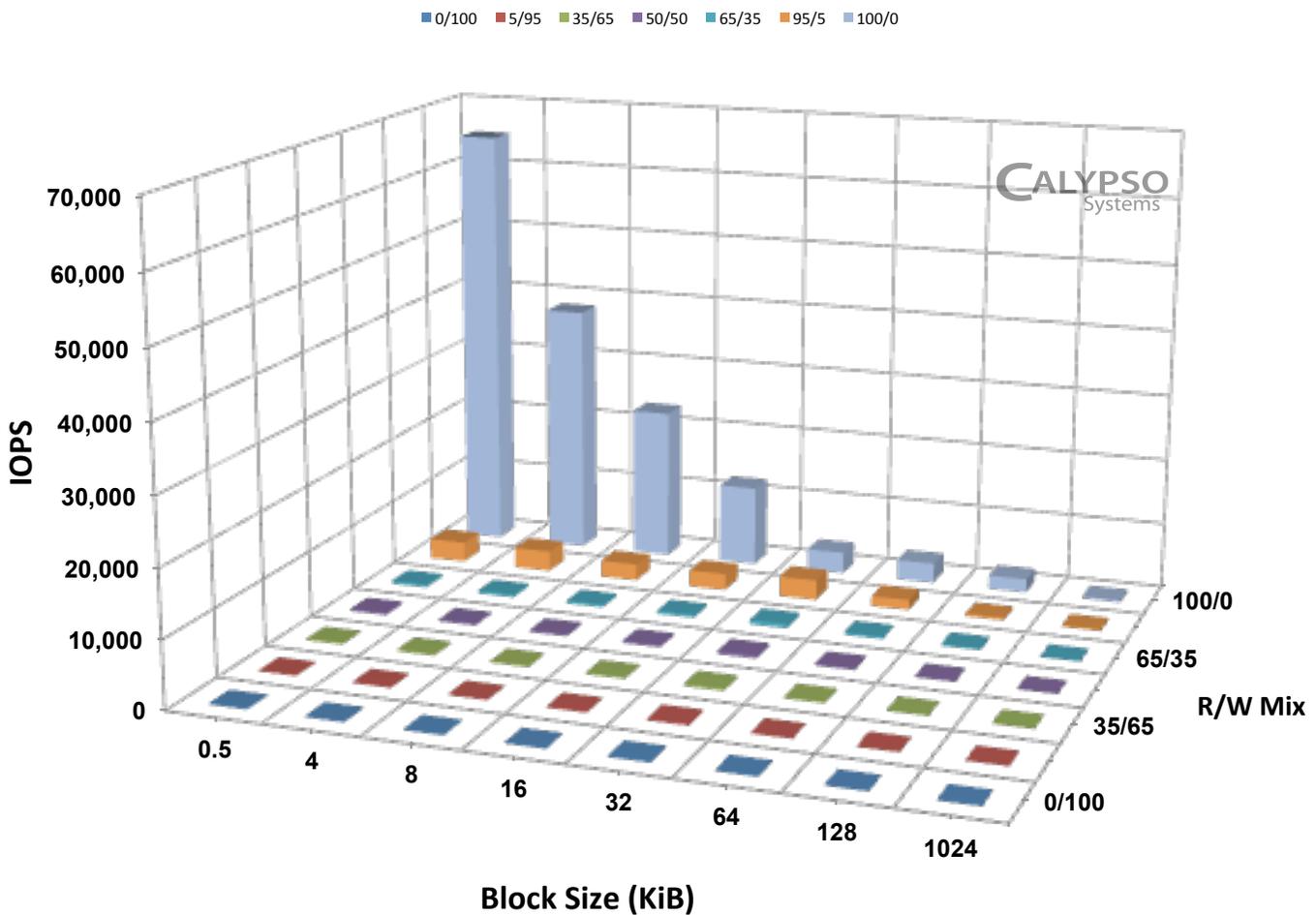
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)

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Device Under Test (DUT)		VENDOR: ABC CO.	SSD MODEL NO: MLC-B 160 GB		TEST SPONSOR	CALYPSO Systems	
Serial No.	0000-1111-FFFF	DUT Preparation		Test Loop Parameters		Steady State	
Firmware Rev	02HD	Purge	Security Erase		REQUIRED:	Convergence	YES
Capacity	160 GB	Pre-Conditioning		Data Pattern		Rounds	9-13
NAND Type	MLC	Workload Independent	2X SEQ/128KiB		Tester's Choice:	PC AR	100%
Device I/F	3 Gb/s SATA		Full IOPS Loop			OIO/Thread (QD)	AR AMOUNT
Test Platform	RTP 2.0 CTS 6.5	Workload Dep.			Thread Count (TC)	AR Segments	2048

IOPS - ALL RW Mix & BS - 3D Columns



MLC-B Test Report

Summary Report Page - THROUGHPUT

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Device Under Test (DUT)

MLC-B

**SNIA SSS PTS
Summary Report**

**Calypso
Systems, Inc.**



DEVICE INFORMATION		TEST HARDWARE PLATFORM		TEST SOFTWARE		REPORT DATE	
SERIAL NO.	0000-1111-FFFF	SYSTEM	Calypso RTP 2.0	SYS OS	CENT OS 5.6	Report	06DEC11
FIRMWARE REV.	02HD	Motherboard/cpu	Intel 5520HC / W5580	SW TOOL	Calypso CTS 6.5	Test Run	01NOV - 04DEC11
USER CAPACITY	MLC 256 GB	RAM	12GB ECC DDR3	SW Rev	1.19.10	Test Sponsor	Calypso
DEVICE INTERFACE	3 Gb/s SATA	Device Interface	LSA 9212-e 6Gb/s HBA	Release	Nov. 2011	Auditor	N/A

Test Description

Purpose	To measure Large Block SEQ TP using different BS and R/W Mixes
Test Outline	PURGE , then apply preconditioning until Steady State is achieved according to the SNIA PTS
Preconditioning	PURGE followed by SNIA PTS prescribed WIPC & WDPC

Test Set Up

PTS-C	TEST	Purge	DP	OIO	WIPC		WDPC		STEADY STATE	
					PC AR	TEST AR	AR AMT	SEGMENTS	WORKLOAD	ROUNDS
9.0	THROUGHPUT - REQUIRED	Security Erase	RND	TC 1 QD 2	100%	100%	16 GB	2048	SEQ 1024KiB	1 - 5

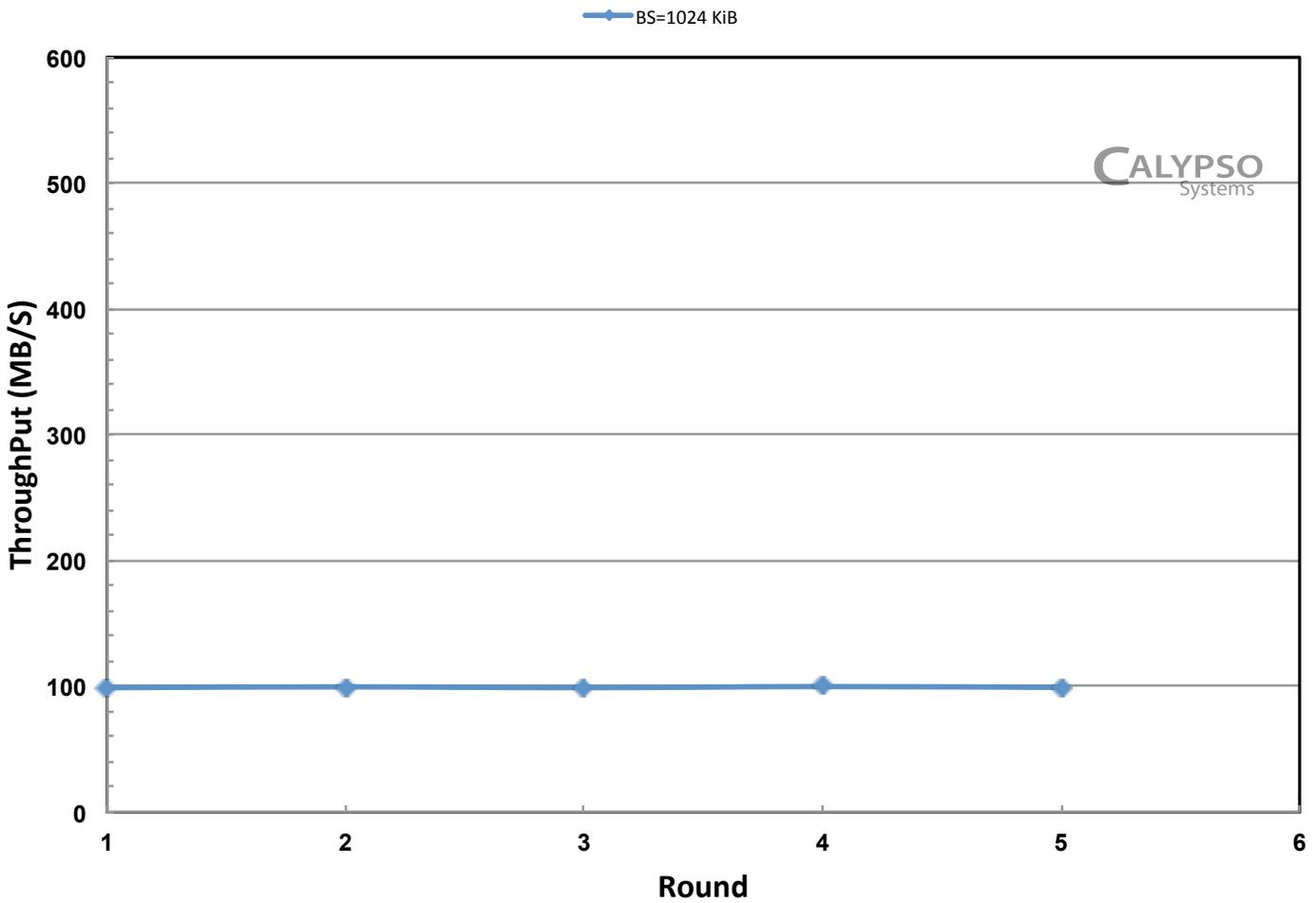
Select Performance Data

	SEQ 1024KiB R	SEQ 1024KiB W
	264 MB/S	99 MB/S

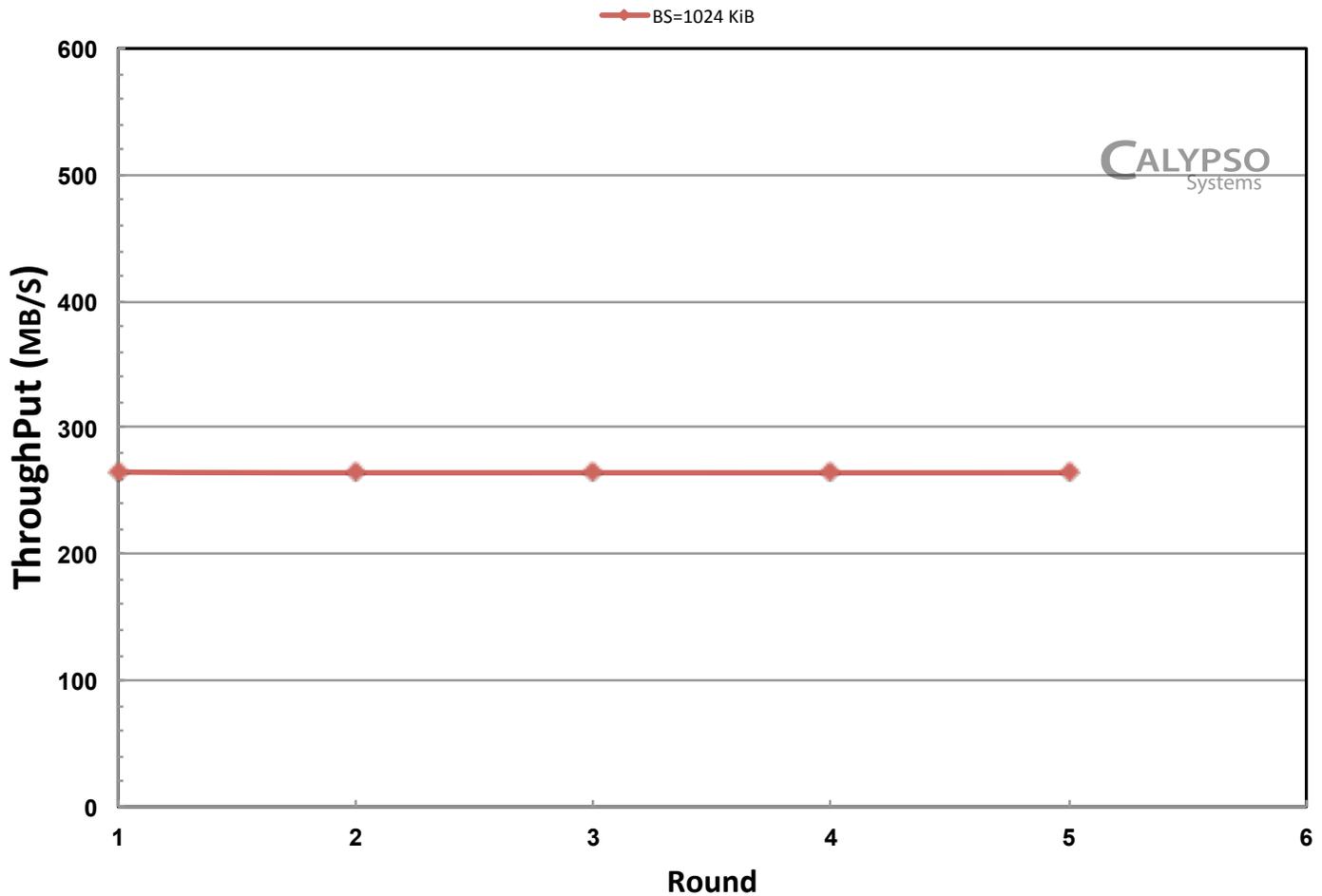
Test Sponsor – Special Notes

ITEM	NOTATION	COMMENTS

Test Run Date: 11/15/2011 12:46 AM		Report Run Date: 11/21/2011 04:50 PM	
Client Throughput Test (REQUIRED) - Report Page			
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)			Rev. PTS-C 1.0
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Device Under Test (DUT)	VENDOR: ABC CO.	SSD MODEL NO: MLC-B 160 GB	TEST SPONSOR CALYPSO Systems
Serial No.	0000-1111-FFFF	DUT Preparation	Test Loop Parameters
Firmware Rev	02HD	Purge	Security Erase
Capacity	160 GB	Pre-Conditioning	
NAND Type	MLC	Workload Independent	2X SEQ/128KiB
Device I/F	3 Gb/s SATA		
Test Platform	RTP 2.0 CTS 6.5	Workload Dep.	SEQ 1024KiB
		REQUIRED:	Data Pattern
		Tester's Choice:	RND
		OIO/Thread (QD)	2
		Thread Count (TC)	1
		Steady State	Convergence
			YES
			Rounds
			1-5
			PC AR
			100%
			AR AMOUNT
			16 GiB
			AR Segments
			2048
Client Throughput Test - SS Convergence - Write			

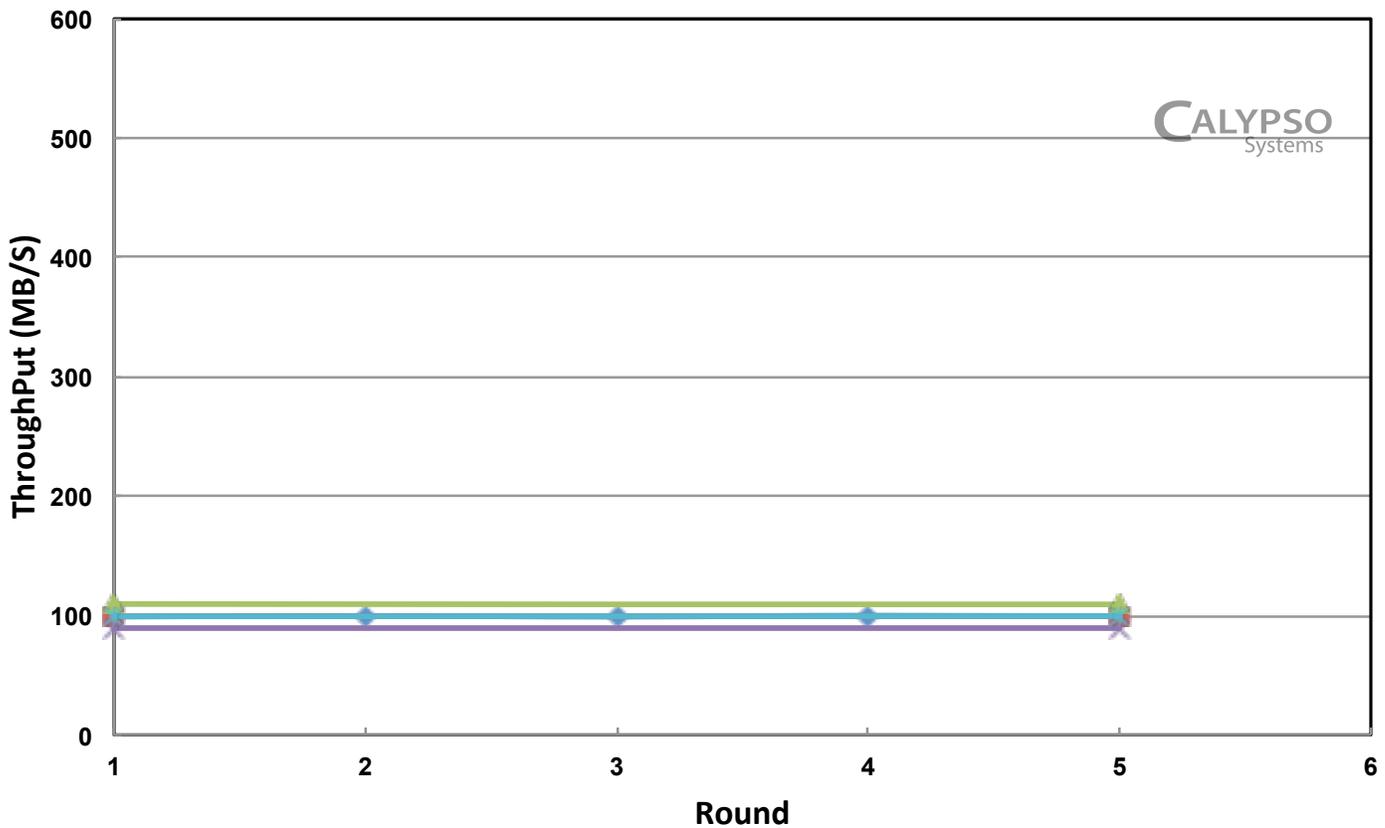


Test Run Date: 11/15/2011 12:46 AM		Report Run Date: 11/21/2011 04:50 PM	
Client Throughput Test (REQUIRED) - Report Page			
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)			Rev. PTS-C 1.0
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Device Under Test (DUT)	VENDOR: ABC CO.	SSD MODEL NO: MLC-B 160 GB	TEST SPONSOR CALYPSO Systems
Serial No.	0000-1111-FFFF	DUT Preparation	Test Loop Parameters
Firmware Rev	02HD	Purge	Security Erase
Capacity	160 GB	REQUIRED:	
NAND Type	MLC	Data Pattern	
Device I/F	3 Gb/s SATA	RND	
Test Platform	RTP 2.0 CTS 6.5	Workload Independent	2X SEQ/128KiB
		Workload Dep.	SEQ 1024KiB
		Tester's Choice:	
		OIO/Thread (QD)	2
		Thread Count (TC)	1
Steady State			
Convergence		YES	
Rounds		1-5	
PC AR		100%	
AR AMOUNT		16 GiB	
AR Segments		2048	
Client Throughput Test - SS Convergence - Read			



Test Run Date: 11/15/2011 12:46 AM		Report Run Date: 11/21/2011 04:50 PM	
Client Throughput Test (REQUIRED) - Report Page			
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)			Rev. PTS-C 1.0
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Device Under Test (DUT)	VENDOR: ABC CO.	SSD MODEL NO: MLC-B 160 GB	TEST SPONSOR CALYPSO Systems
Serial No.	0000-1111-FFFF	DUT Preparation	Test Loop Parameters
Firmware Rev	02HD	Purge	Security Erase
Capacity	160 GB	REQUIRED:	
NAND Type	MLC	Data Pattern	
Device I/F	3 Gb/s SATA	RND	
Test Platform	RTP 2.0 CTS 6.5	Tester's Choice:	
		OIO/Thread (QD)	2
		Thread Count (TC)	1
		Pre-Conditioning	
		Workload Independent	2X SEQ/128KiB
		Workload Dep.	SEQ 1024KiB
Steady State			
Convergence		YES	
Rounds		1-5	
PC AR		100%	
AR AMOUNT		16 GiB	
AR Segments		2048	
Client - Steady State Measurement Window – SEQ/1024 KiB			

◆ IOPS
■ Average
▲ 110%*Average
✱ 90%*Average
◆ Slope



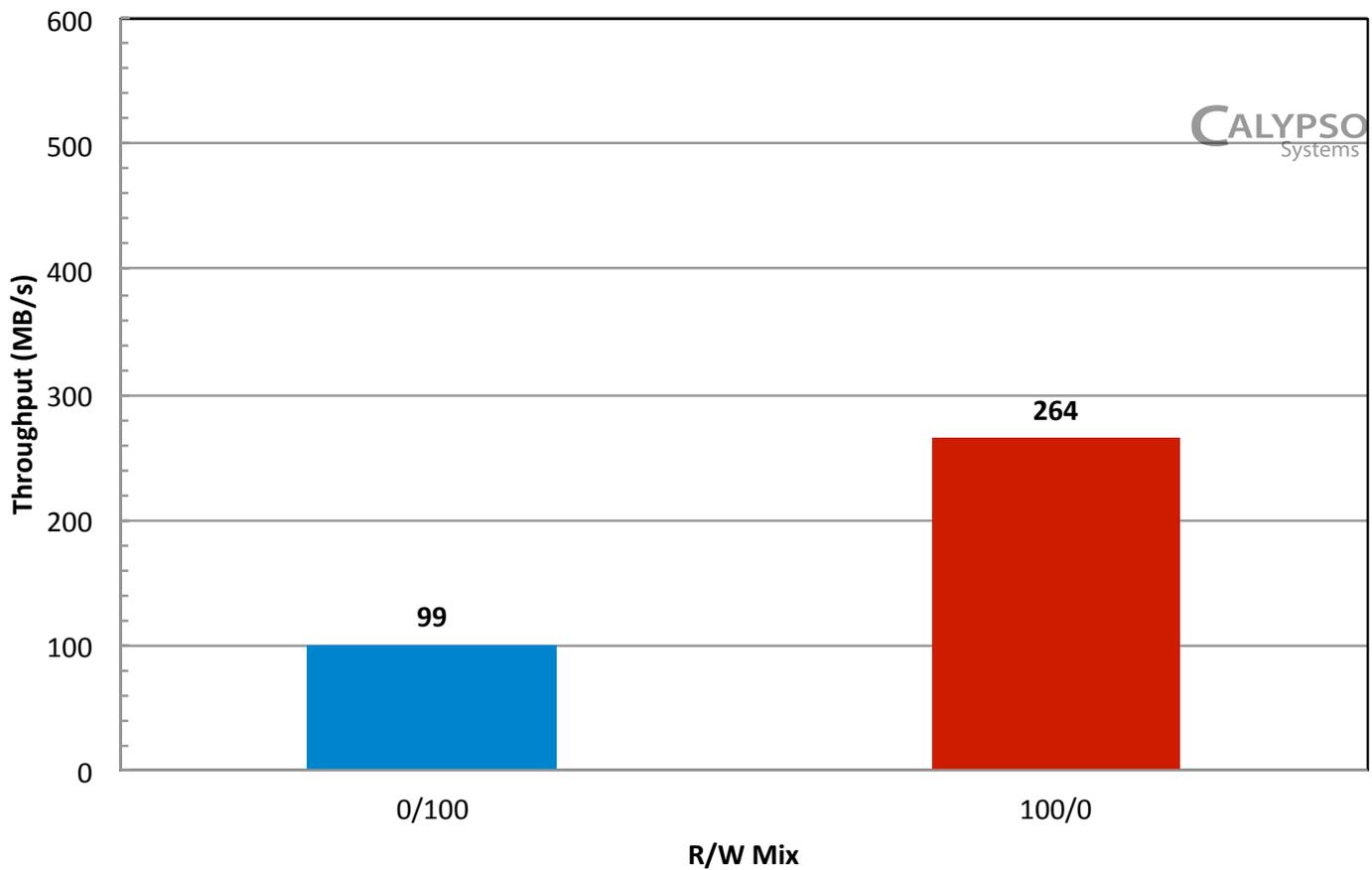
Steady State Determination Data

Average ThroughPut:	99.4		
Allowed Maximum Data Excursion:	19.9	Measured Maximum Data Excursion:	0.9
Allowed Maximum Slope Excursion:	9.9	Measured Maximum Slope Excursion:	0.2
Least Squares Linear Fit Formula:	0.048 * R + 99.264		

Test Run Date: 11/15/2011 12:46 AM		Report Run Date: 11/21/2011 04:50 PM				
Client Throughput Test (REQUIRED) - Report Page						
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)					Rev. PTS-C 1.0	
					Page 4 of 5	
Device Under Test (DUT)		VENDOR: ABC CO.	SSD MODEL NO: MLC-B 160 GB		TEST SPONSOR 	
Serial No.	0000-1111-FFFF	DUT Preparation		Test Loop Parameters		
Firmware Rev	02HD	Purge	Security Erase	REQUIRED:	Steady State	
Capacity	160 GB	Pre-Conditioning			Convergence	YES
NAND Type	MLC	Workload Independent	2X SEQ/128KiB	Data Pattern	Rounds	1-5
Device I/F	3 Gb/s SATA			Workload Dep.	SEQ 1024KiB	Tester's Choice: OIO/Thread (QD) Thread Count (TC)
Test Platform	RTP 2.0 CTS 6.5					
					AR Segments	2048
Client Throughput - ALL RW Mix & BS - Tabular Data						

Block Size (KiB)	Read / Write Mix %	
	0/100	100/0
1024	99.4	264.3

Test Run Date: 11/15/2011 12:46 AM		Report Run Date: 11/21/2011 04:50 PM	
Client Throughput Test (REQUIRED) - Report Page			
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)			Rev. PTS-C 1.0
			Page 5 of 5
Device Under Test (DUT)	VENDOR: ABC CO.	SSD MODEL NO: MLC-B 160 GB	TEST SPONSOR CALYPSO Systems
Serial No.	0000-1111-FFFF	DUT Preparation	Test Loop Parameters
Firmware Rev	02HD	Purge	Security Erase
Capacity	160 GB	REQUIRED:	
NAND Type	MLC	Data Pattern	
Device I/F	3 Gb/s SATA	RND	
Test Platform	RTP 2.0 CTS 6.5	Tester's Choice:	
		OIO/Thread (QD)	2
		Thread Count (TC)	1
		Workload Independent	2X SEQ/128KiB
		Workload Dep.	SEQ 1024KiB
		Convergence	YES
		Rounds	1-5
		PC AR	100%
		AR AMOUNT	16 GiB
		AR Segments	2048
Client Throughput - ALL RW Mix & BS - 2D Plot			



MLC-B Test Report

Summary Report Page - LATENCY

SNIA Solid State Storage Performance Test Specification (PTS)						Rev. PTS 1.0	
						Page 20 of 26	
Device Under Test (DUT)	MLC-B	SNIA SSS PTS Summary Report		Calypso Systems, Inc.		CALYPSO Systems	
DEVICE INFORMATION		TEST HARDWARE PLATFORM		TEST SOFTWARE		REPORT DATE	
SERIAL NO.	0000-1111-FFFF	SYSTEM	Calypso RTP 2.0	SYS OS	CENT OS 5.6	Report	06DEC11
FIRMWARE REV.	02HD	Motherboard/cpu	Intel 5520HC / W5580	SW TOOL	Calypso CTS 6.5	Test Run	01NOV - 04DEC11
USER CAPACITY	MLC 256 GB	RAM	12GB ECC DDR3	SW Rev	1.19.10	Test Sponsor	Calypso
DEVICE INTERFACE	3 Gb/s SATA	Device Interface	LSA 9212-e 6Gb/s HBA	Release	Nov. 2011	Auditor	N/A

Test Description

Purpose	To measure AVE & MAX Response times at selected BS & RW Mixes measured in mSec
Test Outline	PURGE, then apply preconditioning until Steady State is achieved according to the SNIA PTS
Preconditioning	PURGE followed by SNIA PTS prescribed WIPC & WDPC

Test Set Up

PTS-C	TEST	Purge	DP	OIO	WIPC		WDPC		STEADY STATE	
10.0	LATENCY - REQUIRED	Security Erase	RND	TC 1 QD 1	PC AR	TEST AR	AR AMT	SEGMENTS	WORKLOAD	ROUNDS
					100%	100%	16 GiB	2048	LAT LOOP	12 - 16

Select Performance Data

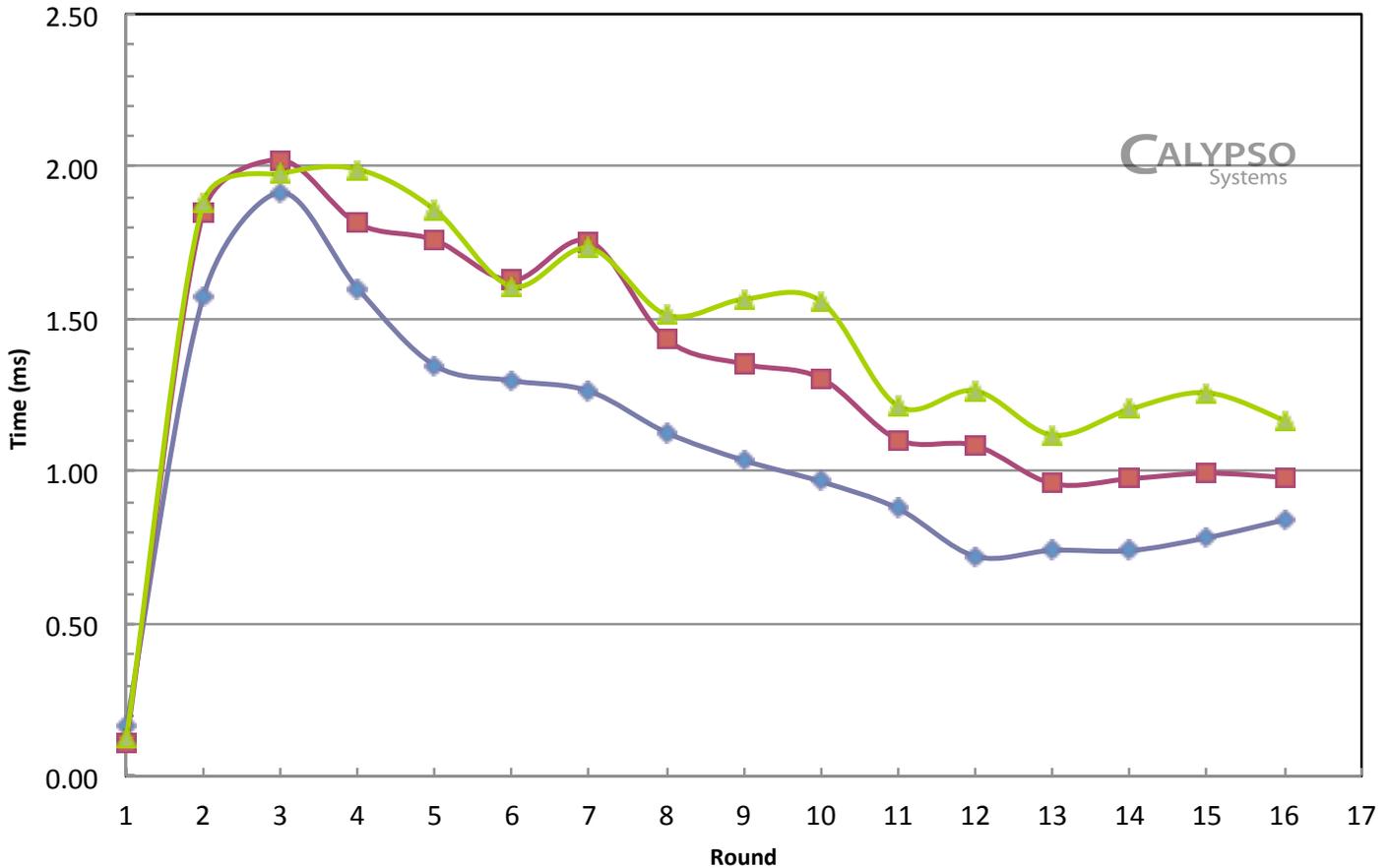
RND 4KiB R AVE	RND 4KiB W AVE	RND 4KiB R MAX	RND 4KiB W MAX
0.190 mSec	1.000 mSec	1.430 mSec	288.3 mSec

Test Sponsor – Special Notes

ITEM	NOTATION	COMMENTS

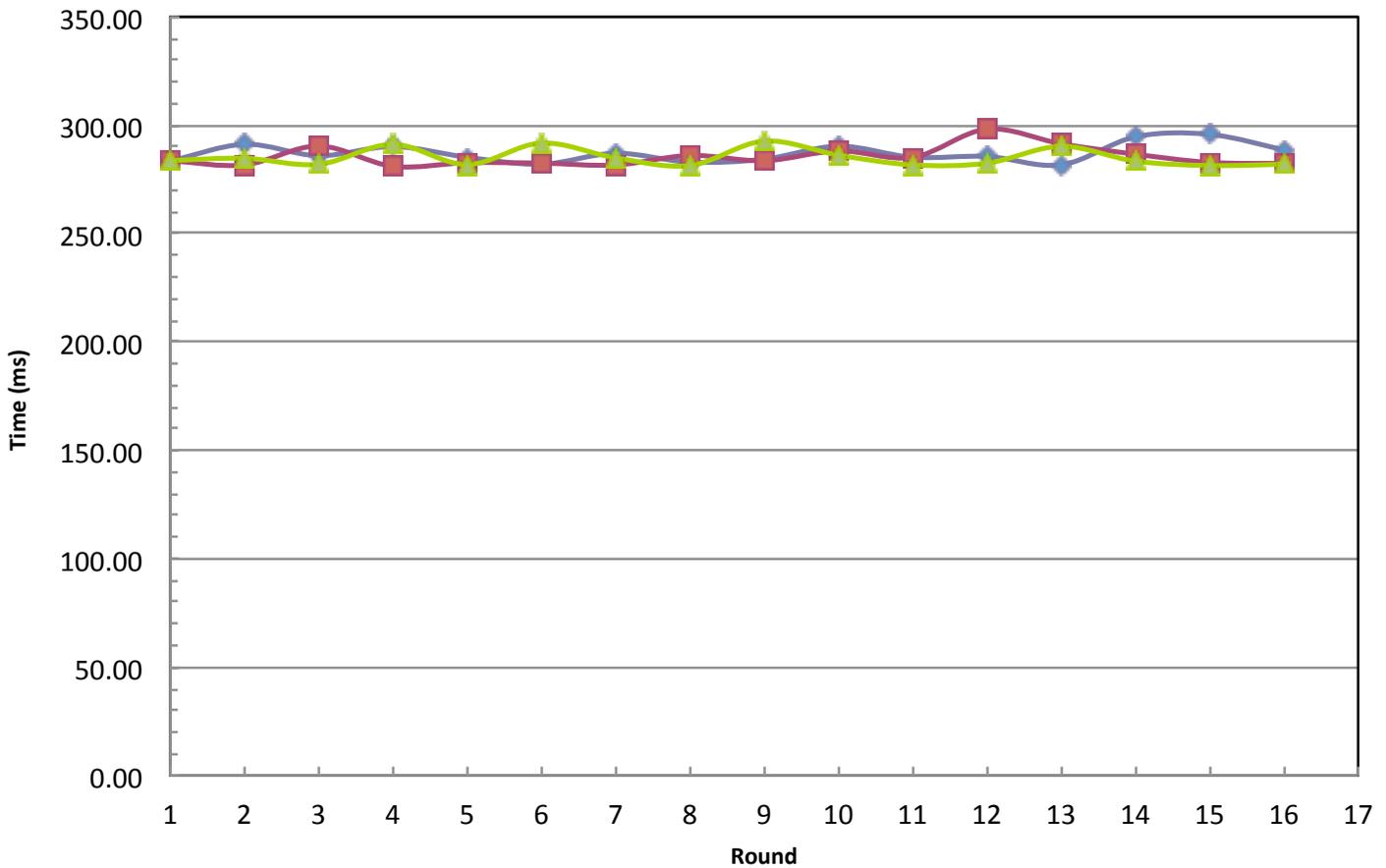
Test Run Date:		11/16/2011 01:01 AM		Report Run Date:		11/22/2011 10:40 AM		
Client Latency (REQUIRED) - Report Page								
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)						Rev.	PTS-C 1.0	
						Page	1 of 6	
Device Under Test (DUT)		VENDOR: ABC CO.	SSD MODEL NO: MLC-B 160 GB		TEST SPONSOR	CALYPSO Systems		
Serial No.	0000-1111-FFFF	DUT Preparation		Test Loop Parameters				Steady State
Firmware Rev	02HD	Purge	Security Erase		REQUIRED:		Convergence	YES
Capacity	160 GB	Pre-Conditioning		Data Pattern		RND	Rounds	12-16
NAND Type	MLC	Workload Independent	2X SEQ/128KiB		Tester's Choice:		PC AR	100%
Device I/F	3 Gb/s SATA		Workload Dep.	Full LAT Loop		OIO/Thread (QD)		AR AMOUNT
Test Platform	RTP 2.0 CTS 6.5			Thread Count (TC)		1	AR Segments	2048
Client - Steady State Convergence Plot – AVE Latency - 100% Writes								

◆ RW=0/100, BS=0.5K
■ RW=0/100, BS=4K
▲ RW=0/100, BS=8K



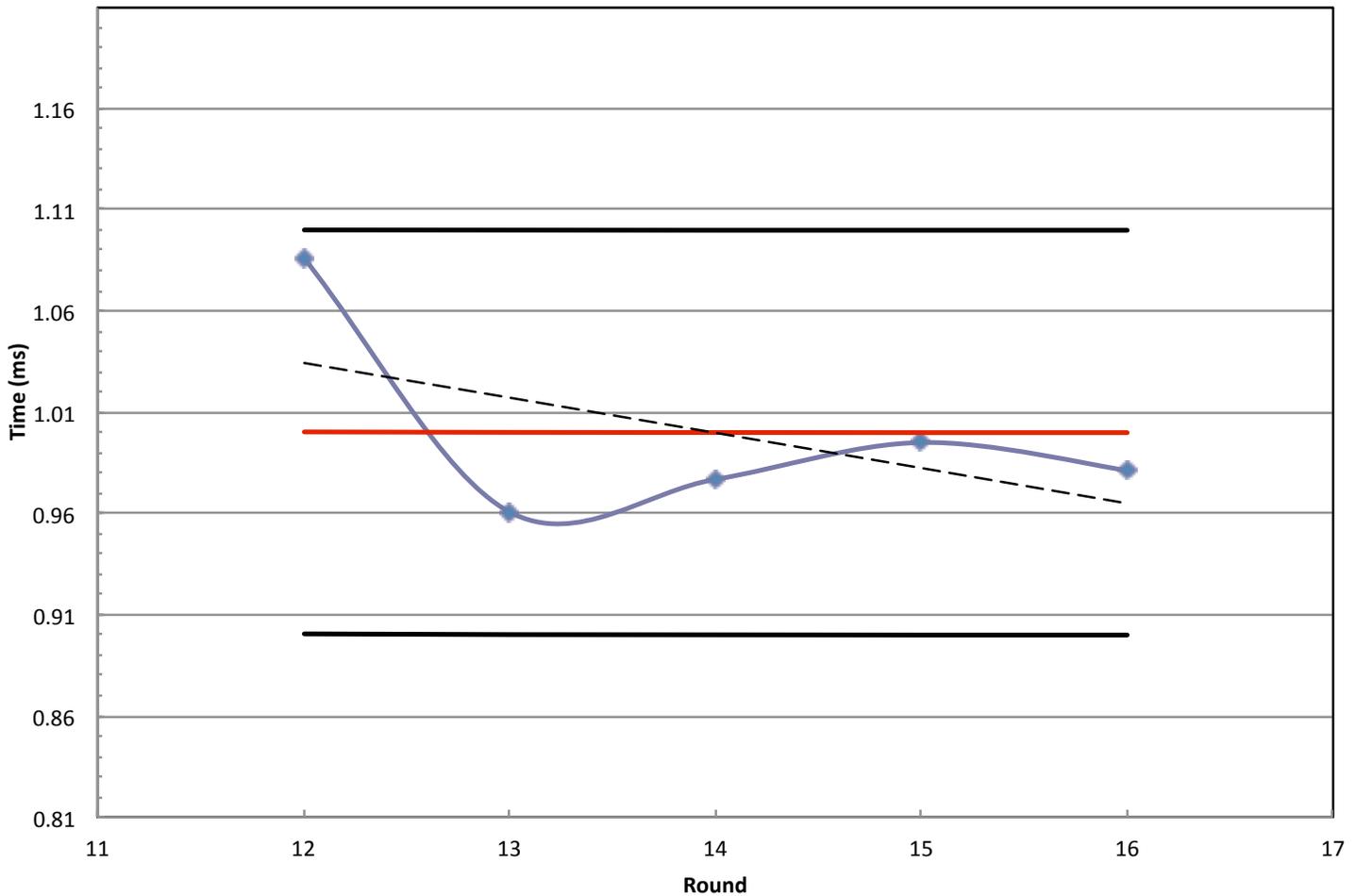
Test Run Date:		11/16/2011 01:01 AM		Report Run Date:		11/22/2011 10:40 AM		
Client Latency (REQUIRED) - Report Page								
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)						Rev.	PTS-C 1.0	
						Page	2 of 6	
Device Under Test (DUT)		VENDOR: ABC CO.	SSD MODEL NO: MLC-B 160 GB		TEST SPONSOR	CALYPSO Systems		
Serial No.	0000-1111-FFFF	DUT Preparation		Test Loop Parameters				Steady State
Firmware Rev	02HD	Purge	Security Erase		REQUIRED:		Convergence	YES
Capacity	160 GB	Pre-Conditioning		Data Pattern		RND	Rounds	12-16
NAND Type	MLC	Workload Independent	2X SEQ/128KiB		Tester's Choice:		PC AR	100%
Device I/F	3 Gb/s SATA		Workload Dep.	Full LAT Loop		OIO/Thread (QD)		AR AMOUNT
Test Platform	RTP 2.0 CTS 6.5			Thread Count (TC)		1	AR Segments	2048
Client - Steady State Convergence Plot - MAX Latency - 100% Writes								

◆ RW=0/100, BS=0.5K
■ RW=0/100, BS=4K
▲ RW=0/100, BS=8K



Test Run Date:		11/16/2011 01:01 AM		Report Run Date:		11/22/2011 10:40 AM		
Client Latency (REQUIRED) - Report Page								
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)						Rev.	PTS-C 1.0	
						Page	3 of 6	
Device Under Test (DUT)		VENDOR:	SSD MODEL NO:		TEST SPONSOR	CALYPSO Systems		
		ABC CO.	MLC-B 160 GB					
Serial No.	0000-1111-FFFF	DUT Preparation		Test Loop Parameters		Steady State		
Firmware Rev	02HD	Purge	Security Erase		REQUIRED:	Convergence	YES	
Capacity	160 GB	Pre-Conditioning		Data Pattern		RND	Rounds	12-16
NAND Type	MLC	Workload Independent	2X SEQ/128KiB		Tester's Choice:	PC AR	100%	
Device I/F	3 Gb/s SATA		Full LAT Loop			OIO/Thread (QD)	1	AR AMOUNT
Test Platform	RTP 2.0 CTS 6.5	Workload Dep.			Thread Count (TC)	1	AR Segments	2048
Client - Steady State Measurement Window – RND/4KiB								

—◆— Ave Latency
— Average
— 110%*Average
- - - 90%*Average



Steady State Determination Data

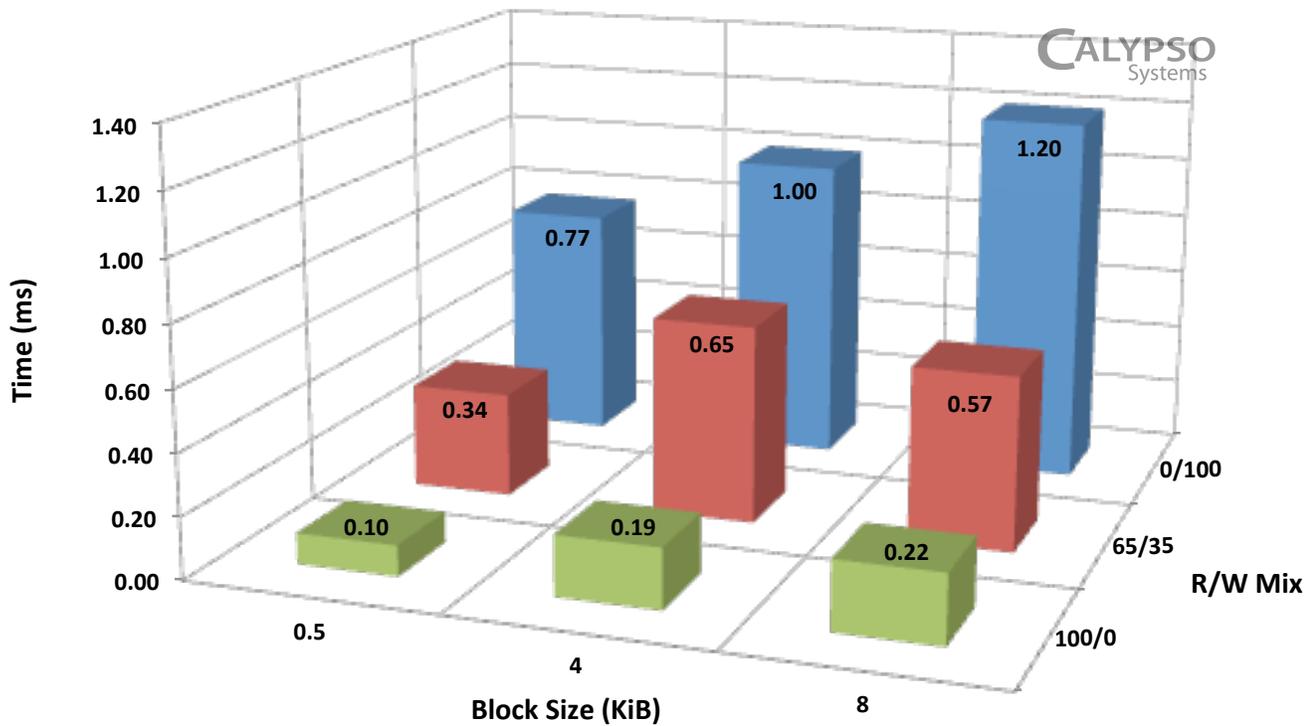
Average Latency (ms):		0.999	
Allowed Maximum Data Excursion:	0.200	Measured Maximum Data Excursion:	0.125
Allowed Maximum Slope Excursion:	0.100	Measured Maximum Slope Excursion:	0.070
Least Squares Linear Fit Formula:		-0.017 * R + 1.244	

Test Run Date:		11/16/2011 01:01 AM		Report Run Date:		11/22/2011 10:40 AM	
Client Latency (REQUIRED) - Report Page							
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)						Rev.	PTS-C 1.0
						Page	4 of 6
Device Under Test (DUT)		VENDOR: ABC CO.	SSD MODEL NO: MLC-B 160 GB		TEST SPONSOR	CALYPSO Systems	
Serial No.	0000-1111-FFFF	DUT Preparation		Test Loop Parameters			
Firmware Rev	02HD	Purge	Security Erase		REQUIRED:	Convergence	YES
Capacity	160 GB	Pre-Conditioning		Data Pattern	RND	Rounds	12-16
NAND Type	MLC	Workload Independent	2X SEQ/128KiB		Tester's Choice:	PC AR	100%
Device I/F	3 Gb/s SATA		Workload Dep.	Full LAT Loop		OIO/Thread (QD)	AR AMOUNT
Test Platform	RTP 2.0 CTS 6.5					Thread Count (TC)	AR Segments
Client - AVE and MAX Response Time - ALL RW Mix & BS - Tabular Data							

Average Response Time (ms)			
	Read / Write Mix %		
Block Size (KiB)	0/100	65/35	100/0
0.5	0.77	0.34	0.10
4	1.00	0.65	0.19
8	1.20	0.57	0.22

Maximum Response Time (ms)			
	Read / Write Mix %		
Block Size (KiB)	0/100	65/35	100/0
0.5	289.26	283.76	1.04
4	288.29	283.21	1.43
8	283.90	269.74	4.77

Test Run Date:		11/16/2011 01:01 AM		Report Run Date:		11/22/2011 10:40 AM		
Client Latency (REQUIRED) - Report Page								
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)						Rev.	PTS-C 1.0	
						Page	5 of 6	
Device Under Test (DUT)		VENDOR:	SSD MODEL NO:		TEST SPONSOR	CALYPSO Systems		
		ABC CO.	MLC-B 160 GB					
Serial No.	0000-1111-FFFF	DUT Preparation		Test Loop Parameters		Steady State		
Firmware Rev	02HD	Purge	Security Erase		REQUIRED:	Convergence	YES	
Capacity	160 GB	Pre-Conditioning		Data Pattern	RND	Rounds	12-16	
NAND Type	MLC	Workload Independent	2X SEQ/128KiB		Tester's Choice:	PC AR	100%	
Device I/F	3 Gb/s SATA	Workload Dep.	Full LAT Loop		OIO/Thread (QD)	1	AR AMOUNT	16 GiB
Test Platform	RTP 2.0 CTS 6.5				Thread Count (TC)	1	AR Segments	2048
Client - AVE Latency vs BS and R/W Mix - 3D Plot								



Test Run Date:		11/16/2011 01:01 AM		Report Run Date:		11/22/2011 10:40 AM		
Client Latency (REQUIRED) - Report Page								
SNIA SSS TWG: Solid State Storage Performance Test Specification (PTS)						Rev.	PTS-C 1.0	
						Page	6 of 6	
Device Under Test (DUT)		VENDOR:	SSD MODEL NO:		TEST SPONSOR	CALYPSO Systems		
		ABC CO.	MLC-B 160 GB					
Serial No.	0000-1111-FFFF	DUT Preparation		Test Loop Parameters		Steady State		
Firmware Rev	02HD	Purge	Security Erase		REQUIRED:	Convergence	YES	
Capacity	160 GB	Pre-Conditioning		Data Pattern	RND	Rounds	12-16	
NAND Type	MLC	Workload Independent	2X SEQ/128KiB		Tester's Choice:	PC AR	100%	
Device I/F	3 Gb/s SATA		Full LAT Loop			OIO/Thread (QD)	1	AR AMOUNT
Test Platform	RTP 2.0 CTS 6.5	Workload Dep.			Thread Count (TC)	1	AR Segments	2048
Client - MAX Latency vs BS and R/W Mix - 3D Plot								

